# Yunho Kim

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#### **Education**

Feb 2009-Feb 2017	Ph. D in Computer Science, KAISI (advisor: Prof. Moonzoo Kim)
	Thesis: Automated Unit Test Generation with Realistic Unit Context Synthesis for Low False
	Alarms
Mar 2007-Feb 2009	M. S. in Computer Science, KAIST (advisor: Prof. Moonzoo Kim)
	<ul> <li>Integrated Master and Ph. D program in computer science</li> </ul>
Mar 2003-Feb 2007	B. S. in Computer Science, KAIST

# **Experience**

Mar 2018-Present	Research Assistant Professor, School of Computing, KAIST
Feb 2017-Feb 2018	Postdoctoral Researcher, Software Testing and Verification(SWTV) group, KAIST
	(advisor: Prof. Moonzoo Kim)

### **Research Interests**

My research interests span software testing and debugging especially for embedded software.

- Automated Software Unit/System Test Generation using Concolic Testing and Mutation Analysis
- Effective Fault Localization using Mutation Analysis and Machine Learning
- Applying Automated Testing and Debugging Techniques to Embedded SW in Industries

# **Publications**

- Refereed international journal articles
- [1] S. Hong, T. Kwak, B. Lee, Y. Jeon, B. Ko, Y. Kim, M. Kim, MUSEUM: Debugging Real-World Multilingual Programs Using Mutation Analysis, Information and Software Technology (IST), vol 82, pages 80-95, Feb 2017
- [2] Z. Xu, Y. Kim, M. Kim, M. Cohen, and G. Rothermel, Directed Test Suite Augmentation: An Empirical Investigation, Journal of Software Testing, Verification and Reliability (STVR), volume 25, issue 2, pages 77-114, March 2015
- [3] M. Kim, Y. Kim, and Y. Choi, Concolic Testing of the Multi-sector Read Operation for Flash Storage Platform Software, Formal Aspects of Computing (FACJ), vol 24, no 2, 2012
- [4] M. Kim, Y. Kim, and H. Kim, A Comparative Study of Software Model Checkers as Unit Testing Tools: An Industrial Case Study, IEEE Transactions on Software Engineering (TSE), vol 37, no 2, March 2011
- Refereed international conference papers
- [1] Y. Kim, S. Hong and M. Kim, Target-driven Compositional Concolic Testing with Function Summary Refinement for Effective Bug Detection, ACM Joint European Software Engineering Conference and Symposium on the Foundations of Software Engineering (ESEC/FSE), Aug 26-30, 2019 (acceptance rate:24.4%)
- [2] Y. Kim, D. Lee, J. Baek, and M. Kim, Concolic Testing for High Test Coverage and Reduced Human Effort in Automotive Industry, Intl. Conf. on Software Engineering (ICSE) Software Engineering In Practice (SEIP) track, May 25-31, 2019 (acceptance rate:25%)

- [3] Y. Kim, Y. Choi, and M. Kim, Precise Concolic Unit Testing of C Programs with Alarm Filtering Using Symbolic Calling Contexts, International Conference on Software Engineering (ICSE), 2018 (acceptance rate:21%)
- [4] Y. Kim, S. Hong, B. Ko, D. Phan, and M. Kim, Invasive Software Testing: Mutating Target Programs to Diversify Test Exploration for High Test Coverage, IEEE International Conference on Software Testing, Verification and Validation (ICST), April 9-13, 2018 (**Distinguished paper award**) (acceptance rate: 25.2%)
- [5] L. Phan, Y. Kim, M. Kim, MUSIC: Mutation Analysis Tool with High Configurability and Extensibility, Mutation Workshop, 2018
- [6] S. Hong, B. Lee, T. Kwak, Y. Jeon, B. Ko, Y. Kim, M. Kim, Mutation Based Fault Localization for Real-World Multilingual Programs, IEEE/ACM International Conference on Automated Software Engineering (ASE), Nov 9-13, 2015 (acceptance rate: 19%)
- [7] **Y. Kim** and M. Kim, SAT-based Bounded Software Model Checking for Embedded Software: A Case Study, Asia-Pacific Software Engineering Conference (APSEC), Dec 1-4 2014 (acceptance rate: 30%)
- [8] Y. Kim, Z. Xu, M. Kim, M. Cohen, and G. Rothermel, Hybrid Directed Test Suite Augmentation: An Interleaving Framework, IEEE International Conference on Software Testing, Verification and Validation (ICST), March 31-April 4, 2014 (acceptance rate: 28%)
- [9] S. Moon, Y. Kim, M. Kim, S. Yoo, Ask the Mutants: Mutating Faulty Programs for Fault Localization, IEEE International Conference on Software Testing, Verification and Validation (ICST), March 31-April 4, 2014 (acceptance rate: 28%)
- [10] Y. Kim, Y. Kim, T. Kim, G. Lee, Y. Jang, and M. Kim, Automated Unit Testing of Large Industrial Embedded Software using Concolic Testing, IEEE/ACM Automated Software Engineering (ASE) Experience track, Nov 11-15, 2013 (acceptance rate:23%)
- [11] **Y. Kim**, M. Kim, Y. Kim, and Y. Jang, Industrial Application of Concolic Testing Approach: A Case Study on libexif by Using CREST-BV and KLEE, Intl. Conf. on Software Engineering (ICSE), Software Engineering in Practice (SEIP) track, June 2-9, 2012 (acceptance ratio:19%)
- [12] M. Kim, Y. Kim, and G. Rothermel, A Scalable Distributed Concolic Testing Approach: An Empirical Evaluation, IEEE International Conference on Software Testing, Verification, and Validation (ICST), April 17-21, 2012 (acceptance ratio: 27%)
- [13] M. Kim, Y. Kim and Y. Jang, Industrial Application of Concolic Testing on Embedded Software: Case Studies, IEEE International Conference on Software Testing, Verification and Validation (ICST) Industrial track, April 17-21, 2012, nominated as a best paper (acceptance ratio: 23%)
- [14] Z. Xu, Y. Kim, M. Kim and G. Rothermel, A Hybrid Directed Test Suite Augmentation Technique, IEEE Intl. Symp. on Software Reliability Engineering (ISSRE), Hiroshima, Japan, Nov 29-Dec 2 2011 (acceptance ratio: 25%)
- [15] M. Kim and Y. Kim, Automated Analysis of Industrial Embedded Software, Automated Technology for Verification and Analysis (ATVA), Taipei, Taiwan, Oct 11-14 2011 (invited paper)
- [16] **Y. Kim** and M. Kim, SCORE: a Scalable Concolic Testing Tool for Reliable Embedded Software, ACM SIGSOFT Foundation of Software Engineering (FSE) Tool demonstration track, pages 420-423, Szeged, Hungary, Sep 5-9 2011 (acceptance ratio: 47%)
- [17] **Y. Kim**, M. Kim and Y. Jang, Concolic Testing on Embedded Software Case Studies on Mobile Platform Programs, ACM SIGSOFT Foundation of Software Engineering (FSE) Industrial track, Sep 5-9, 2011
- [18] Z. Xu, Y. Kim, M. Kim, G. Rothermel, and M. Cohen, Directed Test Suite Augmentation: Techniques and Tradeoffs, ACM SIGSOFT Foundation of Software Engineering (FSE), pages 257-266, Santa Fe, New Mexico, USA, Nov 7-11 2010 (acceptance ratio: 20%)

- [19] Y. Kim, M. Kim, N. Dang, Scalable Distributed Concolic Testing: a Case Study on a Flash Storage Platform, Grand Challenge in Verified Software Track @ Intl. Conf. on Theoretical Aspects of Computing (ICTAC) (LNCS 6255), pages 199-213, Natal, Brazil, Sep 1-3 2010
- [20] M. Kim and Y. Kim, Concolic Testing of the Multi-sector Read Operation for Flash Memory File System, Grand Challenge in Verified Software Track @ Brazilian Symposium on Formal Methods (SBMF), pages 251-265, Gramado, Brazil, Aug 19-21 2009 (LNCS 5902)
- [21] M. Kim, Y. Kim and H. Kim, Unit Testing of Flash Memory Device Driver through a SAT-based Model Checker, IEEE/ACM Automated Software Engineering (ASE), pages 198-207, L'Aquila, Italy, Sep 15-19 2008 (acceptance ratio: 12%)
- [22] M. Kim, Y. Choi, **Y. Kim** and H. Kim, Formal Verification of a Flash Memory Device Driver an Experience Report, Spin Workshop (LNCS 5156), pages 144-159, LA, USA, August 10-12 2008
- [23] M. Kim, Y. Kim, Y. Choi, and H. Kim, Pre-testing Flash Device Driver through Model Checking Techniques, IEEE Intl. Conf. on Software Testing, Verification and Validation (ICST), pages 475-484, Lillehammer, Norway, April 9-11 2008 (acceptance ratio: 20%)

# • Refereed domestic journal articles

- [1] H. Kim, Y. Kim, and M. Kim, Improving Applicability and Usability of a Concolic Testing Tool CROWN, Journal of KIISE: Software and Applications, Vol. 45, No. 10, Oct 2018 (written in Korean)
- [2] H. Lim, Y. Kim, and M. Kim, Automated Capturing and Replaying Unit Inputs of C Programs from System Executions through Static and Dynamic Analysis, Journal of KIISE: Software and Applications, Vol. 45, No. 10, Oct 2018 (written in Korean)
- [3] Y. Kim, H. Kim, W. Yang, and M. Kim, A Comparative Study of C Program Mutation Tools for Effective Mutation Analysis: A Case Study of Proteum and Milu, Journal of KIISE: Software and Applications, Vol. 45, No. 4, Apr 2018 (written in Korean)
- [4] **Y. Kim** and M. Kim, Automated Unit-test Generation for Detecting Vulnerabilities of Android Kernel Modules, Journal of KIISE: Software and Applications, Vol. 44, No. 2, Feb 2017 (written in Korean)
- [5] Y. Jeon, Y. Kim, S. Hong, and M. Kim, Mutagen4J: Effective Mutant Generation Framework for Java Programs, Journal of KIISE: Software and Applications, Vol. 43, No. 9, Sep 2016 (written in Korean)
- [6] Y. Kim, T. Kim, M, Kim, H. Lee, H. Jang, and M. Park, Effective Integer Promotion Bug Detection Technique for Embedded Software, Journal of KIISE: Software and Applications, Journal of KIISE: Software and Applications, Vol. 43, No. 6, Jun 2016 (written in Korean)
- [7] S. Moon, Y. Kim, M. Kim, FEAST: An Enhanced Fault Localization Technique using Probability of Test Cases Executing Faults, Journal of KIISE: Software and Applications, Vol 40, No. 10, Oct 2013 (written in Korean)
- [8] Y. Kim, Y. Park, M. Kim, A Comparative Case Study on Static Program Analysis Tools, Journal of KIISE: Computing Practices and Letters, Vol. 19, No. 8, Aug 2013 (written in Korean)
- [9] Y. Kim, M. Kim, Y. Jang, CREST-BV: An Improved Concolic Testing Technique Supporting Bitwise Operations for Embedded Software, Journal of KIISE: Software and Applications, Vol. 40, No. 2, Feb 2013 (written in Korean)
- [10] Y. Kim, M. Kim, Y. Kim, E. Jung, Comparison of Search Strategies of KLEE Concolic Testing Tool, Vol. 18, No. 4, Apr 2012 (written in Korean)

# Refereed domestic conference papers

- [1] K. Park, J. Lee, H. Song K. Cho, Y. Kim, and M. Kim, Concolic Testing to Improve SW Quality of Defense Weapon System, Korea Software Congress (KSC), Dec 19-21, 2018 (written in Korean)
- [2] S. Hong, Y. Kim, M. Kim, S. Yoon, H. Jung, and S. Park, AtomicitySanitizer: Effective Runtime Atomicity Violation Detector for Multithreaded C Programs, Korea Software Congress (KSC), Dec 19-21, 2018 (written in Korean)
- [3] A. Lee, H. Kim, Y. Kim, and M. Kim, Improvement of Concolic Testing Effectiveness by Supporting Bitfield Symbolic Variable, Korea Computer Congress (KCC), Jun 20-22, 2018 (written in Korean)
- [4] H. Kim, Y. Kim, and M. Kim, Improving Applicability and User Interface of CREST, Korea Conference on Software Engineering (KCSE), Jan 29-31, 2018 (written in Korean) (Best paper award)
- [5] H. Lim, Y. Kim, and M. Kim, Automated Capturing & Replaying Dynamic Unit Inputs of C Programs from System Executions, Korea Software Congress (KSC), Dec 20-22, 2017 (written in Korean) (**Distinguished best paper award**)
- [6] P. Loc, B. Ko, Y. Kim, and M.Kim, COMUT: A Configurable Mutant Generation Tool for C programs for effective and efficient mutation analysis, Korea Software Congress (KSC), Dec 20-22, 2017 (written in Korean) (Best paper award)
- [7] Y. Kim, H. Kim, W. Yang, and M. Kim, A Comparative Study of C Program Mutation Tools for Effective Mutation Analysis: A Case Study of Proteum and Milu, Winter Korea Computer Congress (KCC), Dec 21-23, 2016 (written in Korean) (Best paper award)
- [8] Y. Kim and M. Kim, Automated Unit-test Generation for Detecting Vulnerabilities of Android Kernel Modules, Korea Computer Congress (KCC), Jun 29-Jul 1, 2016 (written in Korean) (Best paper award)
- [9] Y. Kim and M. Kim, Efficient Dynamic Symbolic Execution Search Strategy using Input Coverage, Korea Conference on Software Engineering (KCSE), Jan 27-29, 2016 (written in Korean) (Best short paper award)
- [10] Y. Park, Y. Kim, J. Cho, and M. Kim, Effective Concolic Testing using a Symbolic Library, Korea Conference on Software Engineering (KCSE), Feb 12-14, 2014 (written in Korean) (Best short paper award)
- [11] S. Mun, Y. Kim, M. Kim, Improved Fault Localization Technique using Weighted Test Cases, Korea Conference on Software Engineering (KCSE), Jan 30 Feb 1, 2013 (written in Korean) (**Distinguished best short paper award**)
- [12] Y. Park, Y. Kim, and M. Kim, A Comparative Study of Static Analysis Tools: A Case Study on libexif by Using Coverity and Sparrow, Korea Computer Congress (KCC), Nov 23-24, 2012 (written in Korean) (Best presentation award)
- [13] Y. Kim, M. Kim, and Y. Jang, CREST-BV: An Improved Concolic Testing Technique with Bitwise Operations Support for Embedded Software, Korea Computer Congress(KCC), June 27-19, 2012 (written in Korean) (Best paper award)
- [14] Duc Bui Hoang, **Y. Kim**, and M. Kim, A Case Study of the Application of Dynamic Symbolic Execution to Real-World Binary Programs, Korea Conference on Software Engineering (KCSE), Feb 8-10, 2012
- [15] Y. Kim, Y. Kim, and M. Kim, Case Study on Testing with KLEE Concolic Testing Tool, Korea Computer Congress (KCC), Nov 25-26, 2011 (written in Korean) (Best presentation award)
- [16] **Y. Kim** and M. Kim, Comparison of Test-case Generation Techniques based on Dynamic Symbolic Execution and Genetic Algorithm, Korea Conference on Software Engineering (KCSE), Feb 9-11, 2011 (written in Korean)
- [17] **Y. Kim** and M. Kim, Comparison of Test-case Generation Tools based on Dynamic Symbolic Execution, Koea Conference on Software Engineering (KCSE), Feb 8-10, 2010 (written in Korean)

[18] M. Kim, Y. Kim, and H. Kim, Formal Verification of a Flash Memory Device Driver through Model Checking, Korea Conference on Software Engineering (KCSE), Feb 20-22, 2008 (written in Korean)

### **Research Funding**

- Funding from Korean Government Agencies
- 1. Automated SW Unit Testing based on Unit Correlation Metrics for Accurate Bug Detection, Individual Basic Science & Engineering Research Program supported by national Research Foundation of Korea (NRF), 2017-2019 (KRW 150,000,000)

# **Patents**

- Co-inventor, Application No. 10-2018-0052680 in Korea, Testing Method and Apparatus of Target Function Included in Target Program, May 2018
- 2. Co-inventor, Application No. 10-2018-0053140 in Korea, Testing Method and Apparatus of Target Program using Mutated Program, May 2018
- 3. Co-inventor, Application No. 10-2018-0053145 in Korea, Generating Method and Apparatus of Mutant Programs, Which is Flexible and Highly Scalable, May 2018
- Co-inventor, Patent No. 10-1227024-0000 in Korea, Method of distributed scalable concolic testing for software reliability, Jan 2010

#### Software

- 1. CROWN: Concolic testing for Real-wOrld softWare aNalysis (C++)
  - Available upon request
- 2. MUSIC: MUtation analySIs tool with High Configurability and Extensibility (C++)
  - Available at https://github.com/swtv-kaist/MUSIC

#### **Industry Engineer Training**

- 1. Concolic Testing Theory and Practice with CROWN, May 3, 2019
- 2. SW Engineer Certification for C++, Hyundai Mobis, Aug 1 Oct 31, 2018
- 3. Tutorial of Clang/LLVM C/C++ front-end framework, Hyundai Mobis, Nov 14-15, 2017
- 4. Automated Software Testing for Software Design Engineer in Test (SDET), LG Electronics, Jun 29-30, 2017

#### **Professional Activities**

- International Conference Program Committees
- 1. International Conference on Software Engineering (ICSE) Software Engineering in Practice (SEIP) track, 2020
- 2. International Conference on Software Engineering (ICSE) New Ideas and Emerging Results (NIER) track, 2020
- 3. Working Conference on Verified Software: Theories, Tools, and Experiments (VSTTE), 2019
- 4. International Conference on Software Testing, Verification and Validation (ICST), 2018-2019
  - ICST is enrolled in the best CS conference list made by KIISE(Korean Institute of Information Scientists and Engineers)

- 5. International Conference on Formal Aspects of Component Software (FACS), 2018
- 6. Asia-Pacific Software Engineering Conference (APSEC), 2018

# **Awards and Scholarships**

- 1. IEEE Conference on Software Testing, Validation and Verification(ICST), Distinguished paper award, 2018
  - Y. Kim, S. Hong, B. Ko, L. Phan and M. Kim, Invasive Software Testing: Mutating Target Programs to Diversify Test Exploration for High Test Coverage
- 2. Korea Conference on Software Engineering (KCSE), Best paper award, 2018
  - H. Kim, Y. Kim, and M. Kim, Improving Applicability and User Interface of CREST
- 3. Korea Software Congress (KSC), **Best paper award(1st place)**, 2017
  - H. Lim, **Y. Kim**, and M. Kim, Automated Capturing & Replaying Dynamic Unit Inputs of C Programs from System Executions
- 4. Korea Software Congress (KSC), **Best paper award**, 2017
  - D. Phan, B. Ko, **Y. Kim**, and M. Kim, COMUT: A Configurable Mutant Generation Tool for C programs for effective and efficient mutation analysis
- 5. KAIST School of Computing, **Best Ph.D's dissertation award**, 2017
  - Y. Kim, Automated Unit Test Generation with Realistic Unit Context Synthesis for Low False Alarms
- 6. Samsung HumanTech Paper Competition, **Bronze award**, 2017
  - Y. Kim, Effective Concolic Unit Testing based on Realistic Unit Context Synthesis
- 7. Winter Korea Computer Congress (KCC), **Best paper award**, 2016
  - **Y. Kim,** H. Kim, W. Yang, and M. Kim, A Comparative Study of C Program Mutation Tools for Effective Mutation Analysis: A Case Study of Proteum and Milu
- 8. Korea Computer Congress (KCC), Best paper award, 2016
  - Y. Kim and M. Kim, Automated Unit-test Generation for Detecting Vulnerabilities of Android Kernel Modules
- 9. Korean Institute of Information Scientists and Engineers, 35th Student Research Paper Competition (graduate student track), **Second prize**, Apr 2016
  - Y. Kim, Effective Automated Concolic Unit Testing based on Realistic Unit Context Synthesis
- 10. Korea Conference on Software Engineering (KCSE), Best paper award (short paper), 2016
  - Y. Kim, and M. Kim, Efficient Dynamic Symbolic Execution Search Strategy using Input Coverage
- 11. Samsung HumanTech Paper Competition, Bronze award, 2014
  - S. Moon and Y. Kim, MUSE: Precise Fault Localization based on Program Mutants
- 12. Korea Conference on Software Engineering (KCSE), Best paper award (short paper), 2014
  - Y. Park, Y. Kim, J. Cho, and M. Kim, Effective Concolic Testing using a Symbolic Library
- 13. Korean Institute of Information Scientists and Engineers, 32nd Student Research Paper Competition (graduate student track), **Grand prize**, Apr 2013
  - S. Moon and Y. Kim, FEAST: Coverage-based Fault Localization with Fault Weights on Test Cases
- 14. Korea Computer Congress (KCC), Best presentation award, 2012
  - Y. Park, **Y. Kim**, and M. Kim, A Comparative Study of Static Analysis Tools: A Case Study on libexif by Using Coverity and Sparrow
- 15. Korea Computer Congress (KCC), Best paper award, 2012
  - Y. Kim, M. Kim, and Y. Jang, CREST-BV: An Improved Concolic Testing Technique with Bitwise Operations Support for Embedded Software
- 16. Korea Computer Congress (KCC), Best presentation award, 2011
  - Y. Kim, Y. Kim, M. Kim, Comparison of Search Strategies of KLEE Concolic Testing Tool
- 16. Korea Presidential Science Scholarship, Mar 2003 to Feb 2007

#### **Research Experiences**

# • Government funded projects

- 1. Principal investigator, Automated SW Unit Testing based on Unit Correlation Metrics for Accurate Bug Detection, National Research Foundation of Korea (NRF), 2017-Present
- 2. Researcher, Dynamic and Static SW Data-driven Automated SW Fault Detection and Localization, National Research Foundation of Korea (NRF), 2019-Present
- 3. Researcher, Intelligent Automation Techniques for Verification and Debugging of Fullstack Multilingual Software, National Research Foundation of Korea (NRF), 2017-Present
- 4. Researcher, Automated SW Testing and Debugging Techniques for Improving SW Quality, National Research Foundation of Korea (NRF), 2017-2019
- 5. Research assistant, Automated SW Testing and Debugging Techniques for Improving SW Quality, National Research Foundation of Korea (NRF), 2016-2017
- 6. Research assistant, Behavioural Coverage for Effective Software Testing, National Research Foundation of Korea (NRF), 2014-2016
- 7. Research assistant, Development of Mobile S/W Security Testing Tools for Detecting New Vulnerabilities of Android, Institute for Information and communications Technology Promotion (IITP), 2013-2016
- Research assistant, Research and Development of Dual Operating System Architecture with High-Reliable RTOS and High-Performance OS, Institute for Information and communications Technology Promotion (IITP), 2012-Present
- 9. Research assistant, Practical Dynamic Symbolic Execution for Binary Programs, National Security Research Institute (NSRI), 2011
- 10. Research assistant, Improved Automated Test Case Generation through Parallelized Concolic Testing Technique, National Research Foundation of Korea (NRF), 2010-2011
- 11. Research assistant, Improving Embedded Software Reliability using SAT Solver, National Research Foundation of Korea (NRF), 2008-2009

#### Industry funded project

- 1. Researcher, Application of Concolic Testing for SW Testing Productivity Improvement, Mando, 2019
- 2. Researcher, Dynamic Concurrency Bug Detector for Windows Multi-threaded Programs, Samsung Electronics, 2018
- 3. Researcher, Requirement-based Dynamic Reliability Test Development, LIG Nex1, 2018
- 4. Researcher, Effective Fault Localization using Mutation Analysis, Samsung Electronics, 2017-Present
- 5. Researcher, Automated Dynamic Test Case Generation using Path Search Algorithms, Hyundai Mobis, 2017-Present
- 6. Research assistant, Effective Fault Localization using Mutation Analysis, Samsung Electronics, 2015-2017
- 7. Research assistant, Applying Concolic Testing for Improving Reliability of Automotive Software, Hyundai Motor Company, 2015-2017
- 8. Research assistant, Applying Concolic Testing for Embedded Software Testing Automation, LG Electronics, 2013-2015
- 9. Research assistant, Automated Unit Test Generation Framework by using Concolic Testing, Samsung Electronics, 2010-2014
- 10. Research assistant, Formal Verification of Flash Memory Device Driver, Samsung Electronics, 2007-2008